

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|--------|--|---|------------------|---------|---------------------|
| L1 | 2 | (wafer\$1 or semiconductor\$I or chip\$I or substrat\$1)and classification adj defects and specific adj process and number adj defects and photos and illumination | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 13:17 |
| L2 | 0 | L1 and (first and second)adj wafer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 13:26 |
| L3 | 0 | L1 and (first and second)adj wafer and defect\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 13:26 |
| L4 | 1 | L1 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 13:28 |
| S1 | 571947 | (wafer\$1 or semiconductor\$I or chip\$I or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:27 |
| S2 | 1 | S1 and automatic and defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:29 |
| S3 | 1 | automatic and defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |

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| S4 | 1 | S1 and defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S5 | 1 | defect adj classification and teaching and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S6 | 2 | defect adj classification and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S7 | 82 | defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S8 | 19 | S7 and (wafer\$1 or semiconductor\$1 or chip\$1 or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S9 | 17 | S8 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:36 |
| S10 | 12 | S8 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:36 |
| S11 | 24 | ((DIRK) near2 (SOENKSEN)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:36 |
| S12 | 11 | ((RALF) near2 (FRIEDRICH)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S13 | 1 | ((ANDREAS) near2 (DRAEGER)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S14 | 2 | ((DETLEF) near2 (SCHUPP)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |

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| S16 | 2 | ((THIN) near2 ("VAN LUU")).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:39 |
| S17 | 3 | ((WOLFGANG) near2 (LANGER)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:39 |
| S18 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:40 |
| S19 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:40 |
| S20 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:41 |
| S21 | 0 | S12 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:41 |
| S22 | 0 | S13 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:43 |
| S23 | 3 | S10 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:46 |
| S24 | 638382 | S23 and select\$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:47 |
| S25 | 0 | S23 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:47 |

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| S26 | 18 | S7 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:48 |
| S27 | 0 | S26 and parameters and learning adj node | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:49 |
| S28 | 0 | S26 and parameters and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:49 |
| S29 | 17 | S26 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:49 |
| S30 | 2 | S1 and S7 and S24 and S29 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:56 |
| S31 | 2 | S30 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:56 |
| S32 | 18 | S7 and S26 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:57 |
| S33 | 16 | S32 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:58 |
| S34 | 20 | S1 and automatic and defect adj recognition | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:00 |

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|-----|--------|--|---|----|----|---------------------|
| S35 | 638382 | S34 and select\$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:01 |
| S36 | 4 | S34 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:33 |
| S37 | 1 | S34 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:34 |
| S38 | 0 | S37 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:34 |
| S39 | 16 | S34 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S40 | 0 | S39 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S41 | 2 | S39 and learning | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S42 | 16 | S26 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:39 |
| S43 | 0 | S42 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |

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| S44 | 0 | S42 and learning near mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
| S45 | 0 | S42 and learning near3 mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
| S46 | 11 | S42 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:40 |
| S47 | 598 | S1 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:44 |
| S48 | 340 | S47 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:44 |
| S49 | 1 | S48 and input and user and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:45 |
| S50 | 1 | S48 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:46 |
| S51 | 4 | S48 and alignment adj procedure | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:46 |
| S52 | 0 | S8 and automatic adj defect and recognition and(detect\$3 or determining) same (defect or flaw or fault) same(assign\$3 or test\$3 or evaluat\$3) same descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |

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| S53 | 0 | S48 and automatic adj defect and recognition and(detect\$3 or determining)same (defect or flaw or fault)same(assign\$3 or test\$3 or evaluat\$3)same descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
| S54 | 1 | automatic adj defect and recognition and(detect\$3 or determining)same (defect or flaw or fault)same(assign\$3 or test\$3 or evaluat\$3)same descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
| S55 | 11 | automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S56 | 5 | S55 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S57 | 1 | S56 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S58 | 0 | S57 and edit adj recipe | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:05 |
| S59 | 0 | S57 and edit | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:05 |
| S60 | 0 | S57 and memory adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:07 |
| S61 | 1 | S57 and circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:07 |

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| S62 | 0 | S61 and logic adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:08 |
| S63 | 0 | S61 and blank adj wafer\$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:08 |
| S64 | 1 | S66 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 14:02 |
| S65 | 571947 | (wafer\$1 or semiconductor\$I or chip\$I or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:12 |
| S66 | 2 | S65 and select\$3 and review adj data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:13 |
| S67 | 2 | S65 and review adj data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:13 |
| S68 | 638 | S65 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:14 |
| S69 | 134 | S65 and review same data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:14 |
| S70 | 0 | S69 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |

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| S71 | 0 | S69 and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S72 | 1 | S69 and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S73 | 11 | S68 and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S74 | 5 | S73 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:16 |
| S75 | 5 | S74 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:16 |
| S76 | 1 | S75 and (user or operator or human)and page and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:17 |
| S77 | 1 | S75 and (user or operator or human)and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:17 |
| S78 | 9 | S68 and(detect\$3 or determining) and (defect or fault or flaw)and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:19 |
| S79 | 13 | learning and(knowledge-based or knowledge adj based)and database and automatic and defect adj classification | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |

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| S80 | 10 | S79 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| S81 | 0 | S80 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| S82 | 1 | S80 and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:22 |
| S83 | 8 | S80 and(wafer\$1 or semicondutor\$I or chip\$I or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:24 |
| S84 | 8 | S83 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:24 |
| S85 | 6 | S84 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:43 |
| S86 | 5 | S84 and descriptor adj (defect or fault or flaw) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:46 |
| S87 | 573639 | (wafer\$1 or semicondutor\$I or chip\$I or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:04 |
| S88 | 19 | S87 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:05 |

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| S89 | 640949 | S88 and select\$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:05 |
| S90 | 2 | S88 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:05 |
| S91 | 8 | S87 and display adj thumbnails | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:07 |
| S92 | 2 | S91 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:07 |
| S93 | 0 | S92 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:15 |
| S94 | 8 | S91 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:27 |
| S95 | 1 | S94 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:29 |
| S96 | 2 | S92 and display adj thumbnails | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:30 |
| S97 | 2 | S96 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:30 |

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| S98 | 0 | S97 and circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:31 |
| S99 | 0 | S97 and defect and (classification or classifier or classify) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:32 |
| S100 | 0 | S97 and(classification or classifier or classify or grouping) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:33 |
| S101 | 0 | S97 and intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:33 |
| S102 | 2 | S97 and (intensity or contrast or brightness) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:34 |
| S103 | 2 | S102 and(illumination or source or light) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:34 |
| S104 | 2 | S103 and(blank adj wafer\$1 or wafer\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:36 |
| S105 | 2 | S104 and(polymer or layer or oxide adj layer or contact or metal) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:38 |
| S106 | 0 | S105 and lens | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:39 |

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| S107 | 0 | S105 and focus | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:39 |
| S108 | 0 | S105 and magnificat\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:40 |
| S109 | 2 | S105 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:40 |
| S110 | 2 | S109 and select\$3 adj recipe | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:41 |
| S111 | 2 | "6973209".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:40 |
| S112 | 0 | S111 and alignment | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:40 |
| S113 | 1 | S111 and align\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:40 |
| S114 | 0 | S111 and align\$3 same light | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:41 |
| S115 | 1 | S111 and align\$3 and(light or source or illuminat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:41 |

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| S116 | 1 | S115 and adjusting | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:42 |
| S117 | 0 | S116 and optimal adj intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:42 |
| S118 | 1 | S116 and optimal | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:42 |
| S119 | 0 | S118 and intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:42 |
| S120 | 1 | S118 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:43 |
| S121 | 1 | S120 and algorithm | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:46 |
| S122 | 1 | S121 and automatic | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:47 |
| S123 | 0 | S122 and intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:47 |
| S124 | 1 | S122 and (intensity or contrast or brightness) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:47 |

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| S125 | 0 | S124 and text adj image\$1 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:48 |
| S126 | 0 | S124 and text | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:48 |
| S127 | 1 | S124 and recipe | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:49 |
| S128 | 0 | S127 and review | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:49 |
| S129 | 1 | S127 and dictionary | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:49 |
| S130 | 1 | S129 and registered | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:50 |
| S131 | 1 | S130 and drag | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:51 |
| S132 | 82 | defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:09 |
| S133 | 18 | S132 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:09 |

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|------|----|--|---|----|----|---------------------|
| S134 | 16 | S133 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:09 |
| S135 | 0 | S132 and select\$3 same review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:13 |
| S136 | 5 | S132 and review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:13 |
| S137 | 3 | S136 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:14 |
| S138 | 1 | S137 and descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:19 |
| S139 | 0 | S137 and defect adj descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:20 |
| S140 | 82 | defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:44 |
| S141 | 5 | S140 and review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:44 |
| S142 | 3 | S141 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:44 |

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| S143 | 2 | S142 and(wafer\$1 or semiconductor\$1 or chip\$1 or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:45 |
| S144 | 3 | "6408219".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:46 |
| S145 | 1 | S144 and review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:47 |
| S146 | 1 | S144 and select\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:48 |
| S147 | 732 | select\$3 same review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| S148 | 62 | S147 and(wafer\$1 or semiconductor\$1 or chip\$1 or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| S149 | 0 | S148 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| S150 | 0 | S148 and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| S151 | 14 | S148 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:51 |

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|------|---|---|---|----|----|---------------------|
| S152 | 0 | S151 and display adj thumbnails | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:51 |
| S153 | 0 | S151 and display and thumbnails | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:52 |
| S154 | 0 | S151 and thumbnails | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:52 |
| S155 | 0 | S151 and automatic and defect adj recognition | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:12 |
| S156 | 0 | S151 and select\$3 adj recipe | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:13 |
| S157 | 1 | S151 and align\$3 and(light or source or illuminat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:13 |
| S158 | 0 | S157 and(user or operator or human)and page and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:16 |
| S159 | 0 | S157 and descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:16 |
| S160 | 0 | S157 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:36 |

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|------|--------|--|---|----|----|---------------------|
| S161 | 11 | automatic adj defect and recognition and(defect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| S162 | 5 | S161 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| S163 | 1 | S162 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| S164 | 0 | S163 and memory adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| S165 | 575216 | (wafer\$1 or semiconductor\$1 or chip\$1 or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| S166 | 10 | S165 and automatic adj defect and recognition and(defect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:59 |
| S167 | 643423 | S166 and select\$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:59 |
| S168 | 1 | S166 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:00 |
| S169 | 0 | S168 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:00 |

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|------|------|------------------------------|---|----|----|---------------------|
| S170 | 1 | S166 and memory adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:00 |
| S171 | 0 | S170 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:01 |
| S172 | 4 | S166 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:01 |
| S173 | 0 | S172 and memory adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:01 |
| S174 | 7745 | S165 and memory adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:01 |
| S175 | 2341 | S174 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:01 |
| S176 | 775 | S175 and logic adj circuits | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:02 |
| S177 | 9 | S176 and blank adj wafer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:02 |
| S178 | 8 | S177 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:03 |

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|------|-------|----------------------------|---|----|----|---------------------|
| S179 | 0 | S178 and resist | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:03 |
| S180 | 0 | S178 and photo adj resist | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:03 |
| S181 | 0 | S178 and polymer adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:04 |
| S182 | 51765 | polymer adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:04 |
| S183 | 33269 | S182 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:04 |
| S184 | 2388 | S183 and oxide adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:05 |
| S185 | 1703 | S184 and contact | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:05 |
| S186 | 16332 | S183 and contact | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:05 |
| S187 | 10 | S186 and metal adj later | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:06 |

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|------|---|--|---|----|----|---------------------|
| S188 | 1 | S187 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:06 |
| S189 | 1 | S188 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:06 |
| S190 | 1 | S189 and(intensity or contrast or brightness) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:07 |
| S191 | 0 | S190 and align\$3 and(light or source or illuminat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:07 |
| S192 | 1 | S190 and(light or source or illuminat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:07 |
| S193 | 0 | S192 and magnificat\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:08 |
| S194 | 0 | S192 and lens | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:08 |
| S195 | 0 | S192 and histogram | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:08 |
| S196 | 0 | S195 and focus\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:12 |

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|------|-------|---|---|----|----|---------------------|
| S197 | 51832 | polymer adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S198 | 33269 | S197 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S199 | 16332 | S198 and contact | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S200 | 10 | S199 and metal adj later | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S201 | 1 | S200 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S202 | 1 | S201 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S203 | 1 | S202 and(intensity or contrast or brightness) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S204 | 1 | S203 and(light or source or illuminat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S205 | 0 | S204 and metal adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:05 |

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|------|--------|------------------------------------|---|----|----|---------------------|
| S206 | 1 | S204 and metal | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:06 |
| S207 | 0 | S206 and bright adj field | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:07 |
| S208 | 0 | S206 and bright | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:07 |
| S209 | 1 | S206 and (UV or DUV) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:08 |
| S210 | 0 | S209 and lens | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:08 |
| S211 | 0 | S209 and intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:09 |
| S212 | 1 | S209 and contrast | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:10 |
| S213 | 0 | S212 and histogram | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:10 |
| S214 | 795256 | select\$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:12 |

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|------|------|----------------------------|---|----|----|---------------------|
| S215 | 2665 | S214 and polymer adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:13 |
| S216 | 12 | S215 and bright adj field | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:13 |
| S217 | 9 | S216 and (UV or DUV) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:13 |
| S218 | 3 | S217 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:13 |
| S219 | 3 | S218 and intensity | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:13 |
| S220 | 0 | S219 and histogram | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:14 |
| S221 | 0 | S219 and metal adj layer | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:14 |
| S222 | 0 | S219 and lens | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:14 |
| S223 | 4 | S216 and lens | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:15 |

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|------|--------|---|---|----|----|---------------------|
| S224 | 0 | S223 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:15 |
| S225 | 0 | S223 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:15 |
| S226 | 5025 | 382/149,145,224,159,100,141,155,181.CCLS. | USPAT | OR | ON | 2009/06/29 11:58 |
| S227 | 4478 | 715/774,835,837,764,841,210,839,762,809,804,973,250,866,708.CCLS. | USPAT | OR | ON | 2009/06/29 12:01 |
| S228 | 1453 | 719/310,315.CCLS. | USPAT | OR | ON | 2009/06/29 12:01 |
| S229 | 355 | 714/E11.21.CCLS. | USPAT | OR | ON | 2009/06/29 12:02 |
| S230 | 1846 | 356/237.1,237.2.CCLS. | USPAT | OR | ON | 2009/06/29 12:03 |
| S231 | 834 | 702/35,1,33.CCLS. | USPAT | OR | ON | 2009/06/29 12:04 |
| S232 | 599018 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:29 |
| S233 | 125 | S232 and user adj select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:32 |
| S234 | 3 | S233 and input adj user and page and learning adj mode and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:34 |
| S235 | 4 | S233 and input and user and page and learning adj mode and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:37 |

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|------|----|--|---|----|----|---------------------|
| S236 | 4 | S233 and learning adj mode and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:55 |
| S237 | 1 | S233 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:58 |
| S238 | 11 | automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:59 |
| S239 | 10 | S238 and(wafer\$1 or semicondutor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:59 |
| S240 | 1 | S239 and user adj select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:00 |
| S241 | 1 | S239 and user adj select\$3 and review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:00 |
| S242 | 3 | automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semicondutor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and (illumination or source or light or optimal adj intensity or light adj intensity) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:12 |
| S243 | 3 | automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semicondutor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:16 |
| S244 | 0 | S243 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:17 |

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|------|-----|--|-------|----|----|---------------------|
| S246 | 781 | S226 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:19 |
| S247 | 3 | S246 and user adj select\$3 and review and data adj file | USPAT | OR | ON | 2009/06/29 13:19 |
| S248 | 27 | S246 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:20 |
| S249 | 0 | S248 and input and user and page and learning adj mode and parameters | USPAT | OR | ON | 2009/06/29 13:21 |
| S251 | 0 | S248 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:23 |
| S252 | 0 | S248 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and (illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:24 |
| S253 | 2 | S248 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:25 |
| S254 | 2 | S253 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | USPAT | OR | ON | 2009/06/29 13:28 |
| S255 | 0 | S253 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:32 |
| S256 | 0 | S253 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:43 |
| S257 | 0 | S253 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast)and(detect\$3 or determining)and(defect or flaw or fault) | USPAT | OR | ON | 2009/06/29 13:46 |
| S258 | 18 | S227 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:48 |
| S259 | 4 | S258 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:48 |
| S260 | 0 | S259 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:48 |
| S261 | 0 | S259 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:52 |

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|------|--------|--|---|----|----|---------------------|
| S262 | 2 | S228 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:53 |
| S263 | 0 | S262 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:55 |
| S264 | 0 | S262 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:56 |
| S265 | 0 | S262 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:56 |
| S266 | 2 | S228 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:59 |
| S267 | 1 | S229 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:59 |
| S268 | 0 | S267 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:59 |
| S269 | 0 | S267 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:59 |
| S270 | 0 | S267 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:00 |
| S271 | 733 | S230 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 14:01 |
| S272 | 5 | S271 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:01 |
| S273 | 0 | S272 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:01 |
| S274 | 0 | S272 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:01 |
| S275 | 5 | S272 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | USPAT | OR | ON | 2009/06/29 14:02 |
| S276 | 0 | S272 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:03 |
| S277 | 599018 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |

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|------|--------|--|---|----|----|---------------------|
| S278 | 83 | defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S279 | 19 | S278 and (wafer\$1 or semiconductor\$1 or chip\$1 or subtrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S280 | 12 | S279 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S281 | 3 | S280 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S282 | 685554 | S281 and select\$3 and review and data file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S283 | 18 | S278 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S284 | 17 | S283 and parameters | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S285 | 2 | S277 and S278 and S282 and S284 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| S286 | 0 | S285 and @ad<"20030712" | USPAT | OR | ON | 2009/06/29 14:04 |
| S288 | 129 | S231 and(wafer\$1 or semiconductor\$1 or chip\$1 or subtrat\$1) | USPAT | OR | ON | 2009/06/29 14:06 |

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|------|---|---|---|----|----|---------------------|
| S289 | 4 | S288 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:06 |
| S290 | 0 | S289 and select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:07 |
| S291 | 0 | S289 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:08 |
| S292 | 3 | S289 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | USPAT | OR | ON | 2009/06/29 14:09 |
| S293 | 0 | S292 and select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:23 |
| S294 | 1 | S288 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:26 |
| S295 | 0 | S294 and select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:26 |
| S296 | 0 | S294 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:28 |
| S304 | 1 | ((wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and user adj select\$3 and review and data adj file and input and user and page and learning adj mode).clm. | US-PGPUB | OR | ON | 2009/06/29 14:51 |
| S306 | 1 | S294 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:55 |
| S307 | 0 | S306 and select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and(detect\$3 or determining)and(defect or flaw or fault)and (assign\$3 or test\$3 or evaluat\$3)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:59 |
| S308 | 0 | S306 and select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and(detect\$3 or determining)and(defect or flaw or fault)and (assign\$3 or test\$3 or evaluat\$3)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:59 |
| S309 | 0 | accept\$3 adj select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and(detect\$3 or determining)and(defect or flaw or fault)and (assign\$3 or test\$3 or evaluat\$3)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 15:14 |
| S310 | 0 | accept\$3 adj select\$3 adj(wafer\$1 or semicondutor\$I or chip\$I or substrat\$1)and(capturing or pictures or ccd or camera)and(detect\$3 or determining)and(defect or flaw or fault)and (assign\$3 or test\$3 or evaluat\$3)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 15:15 |

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|------|--------|--|---|----|----|---------------------|
| S311 | 0 | accept\$3 adj select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and(detect\$3 or determining)and(defect or flaw or fault)and (assign\$3 or test\$3 or evaluat\$3)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast)and threshold\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 15:17 |
| S312 | 599764 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:24 |
| S313 | 5 | S312 and (automatic adj defect adj classification or ADC)and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:25 |
| S316 | 0 | S312 and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)same select\$3 adj number same (defect or flaw or fault)same(plurality or plural\$1 or location or first adj wafer or wafer\$1) same(capaturing or obtaining or generating or pictures or thumbnails adj image\$1 or display \$3)same(intensity or contrast or brightness or focus or out adj focus or illumination or source or light or optimal adj illuminat\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:41 |
| S317 | 3 | S313 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:43 |
| S318 | 0 | S313 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:43 |
| S319 | 0 | S313 and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)same select\$3 adj number same (defect or flaw or fault)same(plurality or plural\$1 or location or first adj wafer or wafer\$1) same(capaturing or obtaining or generating or pictures or thumbnails adj image\$1 or display \$3)same(intensity or contrast or brightness or focus or out adj focus or illumination or source or light or optimal adj illuminat\$3)and threshold same descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:46 |
| S320 | 11250 | S313 and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj number and(defect or flaw or fault)and(plurality or plural\$1 or location or first adj wafer or wafer\$1)and (capaturing or obtaining or generating or pictures or thumbnails adj image\$1 or display \$3) and0(intensity or contrast or brightness or focus or out adj focus or illumination or source or light or optimal adj illuminat\$3)and threshold\$3 and descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:47 |
| S321 | 712 | S320 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:47 |

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|------|----|---|---|----|----|---------------------|
| S322 | 1 | S321 and (automatic adj defect adj classification or ADC)and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:48 |
| S325 | 47 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and (assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj number and(defect or flaw or fault)and(plurality or plural\$1 or location or first adj wafer or wafer\$1)and(capaturing or obtaining or generating or pictures or thumbnails adj image\$1 or display\$3)and(intensity or contrast or brightness or focus or out adj focus or illumination or source or light or optimal adj illuminat\$3)and threshold\$3 and descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:52 |
| S326 | 0 | S325 and (automatic adj defect adj classification or ADC)and knowledge adj based adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:53 |
| S327 | 45 | S325 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:53 |
| S328 | 4 | S325 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:53 |
| S329 | 7 | S312 and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)same select\$3 adj number same (defect or flaw or fault)same(plurality or plural\$1 or location or first adj wafer or wafer\$1) same(capaturing or obtaining or generating or pictures or thumbnails adj image\$1 or display \$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:57 |
| S330 | 0 | S329 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 11:57 |
| S332 | 0 | optimizat\$3 and detect\$3 adj parameters and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj number and (defect or flaw or fault)and(plurality or plural\$1 or location or first adj wafer or wafer\$1)and (capaturing or obtaining or generating or pictures or thumbnails adj image\$1 or display\$3) and(intensity or contrast or brightness or focus or out adj focus or illumination or source or light or optimal adj illuminat\$3)and threshold\$3 and descriptors | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/07/02 12:02 |

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